

**Notice of References Cited**

Application/Control No.

10/766,465

Applicant(s)/Patent Under  
Reexamination  
MA ET AL.

Examiner

SU C. KIM

Art Unit

2823

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0019099	02-2002	WILLIAMS et al.	438/270
*	B	US-2001/0026989	10-2001	Thapar, Naresh	438/400
	C	US-			
	D	US-			
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	F	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	JP2000101074		Japan	Uno	
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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